Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/701,183	AKKERMAN ET AL.		
Examiner	Art Unit		
Thanh T. Nguyen	2813		

SEARCHED					
Class	Subclass	Date	Examiner		
	į				
			·		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		<u> </u>		

SEARCH (INCLUDING SEAF		·)
	DATE	EXMR
STIC (see attachment)	7/19/2005	tn